

Form PTO 1449
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LIST OF REFERENCES CITED BY APPLICANT

APPLICANT
Yukihiko NAKANO, et al.FILING DATE
June 25, 2003

GROUP

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
CS	AA	5,216,071	06/01/1993	G. F. HUTTER, et al.			
CS	AB	6,262,207	07/17/2001	P. S. RAO, et al.			
	AC						
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	AI						
	AJ						
	AK						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
CS	AL	1 158 030	11/28/2001	EUROPE		
	AM					
	AN					
	AO					

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

CS	AP	Derwent Abstracts, AN 1993-408874, XP-002256607, JP 05-306332, November 19, 1993
	AQ	Derwent Abstracts, AN 1979-31909B/197917, JP 54-058504, May 11, 1979
	AR	Derwent Abstracts, AN 1995-380274/199549, JP 7-258591, October 9, 1995
	AS	Derwent Abstracts, AN 1995-390479/199550, JP 7-268260, October 17, 1995
	AT	Derwent Abstracts, AN 2000-550950/200051, JP 2000-239591, September 5, 2000
	AU	Derwent Abstracts, AN 1991-114504/199116, JP 3-056573, March 12, 1991
	AV	Derwent Abstracts, AN 1991-248091/199134, JP 3-160069, July 10, 1991
	AW	Derwent Abstracts, AN 2002-100088/200214, JP 2001-262039, September 26, 2001
	AX	Derwent Abstracts, AN 2001-618266/200172, JP 2001-247796, September 11, 2001
	AY	Derwent Abstracts, AN 1997-418016/199739, JP 9-286939, November 4, 1997
✓	AZ	Derwent Abstracts, AN 2000-482652/200042, WO 2000/ 39226, July 6, 2000
		<input type="checkbox"/> Additional References sheet(s) attached

Examiner

Cecile Shusho

Date Considered

3/31/05

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.